## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination LIM ET AL. | Examiner | Art Unit | Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2001/0009439 A1	07-2001	Hwang, Jeong Hwan	348/232
*	В	US-2001/0045988 A1	11-2001	Yamauchi et al.	348/273
*	С	US-2002/0018138 A1	02-2002	Yoshiro, Yamazaki	348/333.05
*	D	US-2002/0097323 A1	07-2002	Ito, Takeyoshi	348/207
*	Е	US-2002/0101515 A1	08-2002	Yoshida et al.	348/211
*	F	US-2002/0194414 A1	12-2002	Bateman et al.	710/303
*	G	US-6,549,958 B1	04-2003	Kuba, Hirokazu	710/14
*	Η	US-2003/0149816 A1	08-2003	Poo et al.	710/62
	1	US-			
	J	US-			
	к	US-			
	٦	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	α					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	×	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.